

<b>Issue Classification</b>		Application/Control No. 10500603	Applicant(s)/Patent under Reexamination OOSAWA ET AL.
		Examiner Hanen, Devin	Art Unit 3745
			

ORIGINAL		INTERNATIONAL CLASSIFICATION					
CLASS	SUBCLASS	CLAIMED				NON-CLAIMED	
		F	O	4	D	25 / 16	
415	68	F	O	1	D	1 / 24	
<b>CROSS REFERENCE(S)</b>							
CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)							
415	199.5						
416	126	198R					
 <b>Devin Hanan</b> Assistant Examiner 7/28/2006 (Date)							
 <b>EDWARD K. LOOK</b> SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 - 7/28/06							
				<b>Total Claims Allowed:</b> <b>12</b>			
(Legal Instruments Examiner)		(Primary Examiner)	(Date)	O.G. Print Claim(s) 1	O.G. Print Figure 1	<b>O.G. Print Figure 1</b>	

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